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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	37325
Number of Logic Elements/Cells	477760
Total RAM Bits	35205120
Number of I/O	380
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	900-BBGA, FCBGA
Supplier Device Package	901-FCBGA (31x31)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7k480t-1ffg901c

Table 2: **Recommended Operating Conditions (1) *(Cont'd)***

Symbol	Description	Min	Typ	Max	Units
$V_{MGTAVTTRCAL}$ (8)	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	1.17	1.2	1.23	V
XADC					
V_{CCADC}	XADC supply relative to GNDADC	1.71	1.80	1.89	V
V_{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
Temperature					
T_j	Junction temperature operating range for commercial (C) temperature devices	0	–	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	–	100	°C
	Junction temperature operating range for industrial (I) temperature devices	–40	–	100	°C

Notes:

1. All voltages are relative to ground.
2. V_{CCINT} and V_{CCBRAM} should be connected to the same supply.
3. Configuration data is retained even if V_{CCO} drops to 0V.
4. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
5. The lower absolute voltage specification always applies.
6. A total of 200 mA per bank should not be exceeded.
7. V_{CCBATT} is required only when using bitstream encryption. If battery is not used, connect V_{CCBATT} to either ground or V_{CCAUX}.
8. Each voltage listed requires the filter circuit described in UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide*.
9. For data rates ≤ 10.3125 Gb/s, $V_{MGTAVCC}$ should be 1.0V ±3% for lower power consumption.
10. For lower power consumption, $V_{MGTAVCC}$ should be 1.0V ±3% over the entire CPLL frequency range.

Table 3: **DC Characteristics Over Recommended Operating Conditions**

Symbol	Description	Min	Typ(1)	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	–	–	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	1.5	–	–	V
I_{REF}	V_{REF} leakage current per pin	–	–	15	µA
I_L	Input or output leakage current per pin (sample-tested)	–	–	15	µA
C_{IN} (2)	Die input capacitance at the pad	–	–	8	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 3.3V	90	–	330	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 2.5V	68	–	250	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.8V	34	–	220	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.5V	23	–	150	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.2V	12	–	120	µA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 3.3V	68	–	330	µA
	Pad pull-down (when selected) @ V_{IN} = 1.8V	45	–	180	µA
I_{CCADC}	Analog supply current, analog circuits in powered up state	–	–	25	mA
I_{BATT} (3)	Battery supply current	–	–	150	nA

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in ISE® software 14.3 v1.07 for the -3, -2, -2L(1.0V), -1, and v1.06 for -2L(0.9V) speed grades.

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Kintex-7 FPGAs.

Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. Table 14 correlates the current status of each Kintex-7 device on a per speed grade basis.

Table 14: **Kintex-7 Device Speed Grade Designations**

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7K70T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K160T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K325T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K355T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K410T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K420T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K480T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)

Table 19: **3.3V IOB High Range (HR) Switching Characteristics *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
HSTL_I_F	0.61	0.64	0.73	0.79	1.10	1.19	1.23	1.41	1.86	2.05	2.22	1.92	ns
HSTL_II_F	0.61	0.64	0.73	0.78	1.05	1.18	1.28	1.42	1.81	2.04	2.27	1.94	ns
HSTL_I_18_F	0.64	0.67	0.76	0.79	1.05	1.18	1.28	1.44	1.81	2.04	2.27	1.95	ns
HSTL_II_18_F	0.64	0.67	0.76	0.79	1.03	1.14	1.23	1.42	1.79	2.00	2.22	1.94	ns
DIFF_HSTL_I_F	0.63	0.67	0.77	0.78	1.09	1.18	1.22	1.48	1.85	2.04	2.21	2.00	ns
DIFF_HSTL_II_F	0.63	0.67	0.77	0.79	1.02	1.11	1.14	1.48	1.78	1.97	2.13	2.00	ns
DIFF_HSTL_I_18_F	0.65	0.69	0.78	0.79	1.08	1.17	1.21	1.48	1.84	2.03	2.20	2.00	ns
DIFF_HSTL_II_18_F	0.65	0.69	0.78	0.81	1.01	1.10	1.13	1.48	1.77	1.96	2.12	2.00	ns
LVCMOS33_S4	1.31	1.40	1.60	1.54	5.23	5.61	6.09	4.13	5.99	6.47	7.08	4.64	ns
LVCMOS33_S8	1.31	1.40	1.60	1.54	4.46	4.85	5.33	3.84	5.22	5.71	6.32	4.36	ns
LVCMOS33_S12	1.31	1.40	1.60	1.54	3.46	3.89	4.42	3.41	4.22	4.75	5.41	3.92	ns
LVCMOS33_S16	1.31	1.40	1.60	1.54	3.06	3.43	3.88	3.72	3.82	4.29	4.87	4.23	ns
LVCMOS33_F4	1.31	1.40	1.60	1.54	4.70	5.01	5.36	3.58	5.46	5.87	6.35	4.09	ns
LVCMOS33_F8	1.31	1.40	1.60	1.54	3.62	4.04	4.56	3.06	4.38	4.90	5.55	3.58	ns
LVCMOS33_F12	1.31	1.40	1.60	1.54	2.57	2.85	3.15	2.88	3.33	3.71	4.14	3.39	ns
LVCMOS33_F16	1.31	1.40	1.60	1.54	2.44	2.69	2.96	2.88	3.20	3.55	3.95	3.39	ns
LVCMOS25_S4	1.08	1.16	1.32	1.36	4.49	4.80	5.16	3.44	5.25	5.66	6.15	3.95	ns
LVCMOS25_S8	1.08	1.16	1.32	1.36	3.66	4.04	4.49	3.20	4.42	4.90	5.48	3.72	ns
LVCMOS25_S12	1.08	1.16	1.32	1.36	2.77	3.10	3.49	2.80	3.53	3.96	4.48	3.31	ns
LVCMOS25_S16	1.08	1.16	1.32	1.36	3.24	3.62	4.09	3.14	4.00	4.48	5.08	3.66	ns
LVCMOS25_F4	1.08	1.16	1.32	1.36	3.96	4.31	4.72	3.06	4.72	5.17	5.71	3.58	ns
LVCMOS25_F8	1.08	1.16	1.32	1.36	2.43	2.87	3.42	2.50	3.19	3.73	4.41	3.02	ns
LVCMOS25_F12	1.08	1.16	1.32	1.36	2.23	2.63	3.13	2.48	2.99	3.49	4.12	3.00	ns
LVCMOS25_F16	1.08	1.16	1.32	1.36	1.92	2.17	2.45	2.33	2.68	3.03	3.44	2.84	ns
LVCMOS18_S4	0.64	0.66	0.74	0.87	3.24	3.45	3.66	1.91	4.00	4.31	4.65	2.42	ns
LVCMOS18_S8	0.64	0.66	0.74	0.87	2.58	2.91	3.31	2.50	3.34	3.77	4.30	3.02	ns
LVCMOS18_S12	0.64	0.66	0.74	0.87	2.58	2.91	3.31	2.50	3.34	3.77	4.30	3.02	ns
LVCMOS18_S16	0.64	0.66	0.74	0.87	1.82	2.03	2.24	1.84	2.58	2.89	3.23	2.36	ns
LVCMOS18_S24(1)	0.64	0.66	0.74	0.87	1.74	1.92	2.08	1.92	2.50	2.78	3.07	2.44	ns
LVCMOS18_F4	0.64	0.66	0.74	0.87	3.12	3.31	3.49	1.77	3.88	4.17	4.48	2.28	ns
LVCMOS18_F8	0.64	0.66	0.74	0.87	1.91	2.13	2.36	2.00	2.67	2.99	3.35	2.52	ns
LVCMOS18_F12	0.64	0.66	0.74	0.87	1.91	2.13	2.36	2.00	2.67	2.99	3.35	2.52	ns
LVCMOS18_F16	0.64	0.66	0.74	0.87	1.52	1.68	1.81	1.72	2.28	2.54	2.80	2.23	ns
LVCMOS18_F24(1)	0.64	0.66	0.74	0.87	1.34	1.46	1.55	1.66	2.10	2.32	2.54	2.17	ns
LVCMOS15_S4	0.66	0.69	0.81	0.90	3.48	3.74	4.03	2.22	4.24	4.60	5.02	2.73	ns
LVCMOS15_S8	0.66	0.69	0.81	0.90	2.37	2.67	3.01	2.41	3.13	3.53	4.00	2.92	ns
LVCMOS15_S12	0.66	0.69	0.81	0.90	1.83	2.03	2.23	1.91	2.59	2.89	3.22	2.42	ns

Table 20: **1.8V IOB High Performance (HP) Switching Characteristics**

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
LVDS	0.75	0.79	0.92	0.89	1.05	1.17	1.24	1.43	1.68	1.92	2.06	2.04	ns
HSUL_12	0.69	0.72	0.82	0.95	1.65	1.84	2.05	1.80	2.29	2.59	2.87	2.41	ns
DIFF_HSUL_12	0.69	0.72	0.82	0.92	1.65	1.84	2.05	1.47	2.29	2.59	2.87	2.08	ns
HSTL_I_S	0.68	0.72	0.82	0.84	1.15	1.28	1.38	1.46	1.79	2.03	2.20	2.07	ns
HSTL_II_S	0.68	0.72	0.82	0.84	1.05	1.17	1.26	1.44	1.69	1.93	2.08	2.05	ns
HSTL_I_18_S	0.70	0.72	0.82	0.86	1.12	1.24	1.34	1.41	1.75	2.00	2.16	2.02	ns
HSTL_II_18_S	0.70	0.72	0.82	0.86	1.06	1.18	1.26	1.44	1.70	1.94	2.08	2.05	ns
HSTL_I_12_S	0.68	0.72	0.82	0.94	1.14	1.27	1.37	1.43	1.78	2.02	2.20	2.04	ns
HSTL_I_DCI_S	0.68	0.72	0.82	0.78	1.11	1.23	1.33	1.36	1.74	1.99	2.15	1.98	ns
HSTL_II_DCI_S	0.68	0.72	0.82	0.78	1.05	1.17	1.26	1.33	1.69	1.93	2.08	1.94	ns
HSTL_II_T_DCI_S	0.70	0.72	0.82	0.76	1.15	1.28	1.38	1.40	1.78	2.03	2.20	2.01	ns
HSTL_I_DCI_18_S	0.70	0.72	0.82	0.76	1.11	1.23	1.33	1.36	1.74	1.99	2.15	1.98	ns
HSTL_II_DCI_18_S	0.70	0.72	0.82	0.76	1.05	1.16	1.24	1.32	1.69	1.92	2.06	1.93	ns
HSTL_II _T_DCI_18_S	0.70	0.72	0.82	0.76	1.11	1.23	1.33	1.36	1.74	1.99	2.15	1.98	ns
DIFF_HSTL_I_S	0.75	0.79	0.92	0.89	1.15	1.28	1.38	1.47	1.79	2.03	2.20	2.08	ns
DIFF_HSTL_II_S	0.75	0.79	0.92	0.89	1.05	1.17	1.26	1.47	1.69	1.93	2.08	2.08	ns
DIFF_HSTL_I_DCI_S	0.75	0.79	0.92	0.76	1.15	1.28	1.38	1.47	1.78	2.03	2.20	2.08	ns
DIFF_HSTL_II_DCI_S	0.75	0.79	0.92	0.76	1.05	1.17	1.26	1.40	1.69	1.93	2.08	2.01	ns
DIFF_HSTL_I_18_S	0.75	0.79	0.92	0.89	1.12	1.24	1.34	1.46	1.75	2.00	2.16	2.07	ns
DIFF_HSTL_II_18_S	0.75	0.79	0.92	0.89	1.06	1.18	1.26	1.47	1.70	1.94	2.08	2.08	ns
DIFF_HSTL_I_DCI_18_S	0.75	0.79	0.92	0.75	1.11	1.23	1.33	1.46	1.74	1.99	2.15	2.07	ns
DIFF_HSTL_II_DCI_18_S	0.75	0.79	0.92	0.75	1.05	1.16	1.24	1.41	1.69	1.92	2.06	2.02	ns
DIFF_HSTL_II _T_DCI_18_S	0.75	0.79	0.92	0.76	1.11	1.23	1.33	1.46	1.74	1.99	2.15	2.07	ns
HSTL_I_F	0.68	0.72	0.82	0.84	1.02	1.14	1.22	1.26	1.66	1.90	2.04	1.87	ns
HSTL_II_F	0.68	0.72	0.82	0.84	0.97	1.08	1.15	1.29	1.61	1.84	1.97	1.90	ns
HSTL_I_18_F	0.70	0.72	0.82	0.86	1.04	1.16	1.24	1.32	1.68	1.91	2.06	1.93	ns
HSTL_II_18_F	0.70	0.72	0.82	0.86	0.98	1.09	1.16	1.35	1.62	1.85	1.98	1.96	ns
HSTL_I_12_F	0.68	0.72	0.82	0.94	1.02	1.13	1.21	1.26	1.65	1.88	2.03	1.87	ns
HSTL_I_DCI_F	0.68	0.72	0.82	0.78	1.04	1.16	1.24	1.30	1.67	1.91	2.06	1.91	ns
HSTL_II_DCI_F	0.68	0.72	0.82	0.78	0.97	1.08	1.15	1.22	1.61	1.84	1.97	1.83	ns
HSTL_II_T_DCI_F	0.70	0.72	0.82	0.76	1.02	1.14	1.22	1.26	1.66	1.90	2.04	1.87	ns
HSTL_I_DCI_18_F	0.70	0.72	0.82	0.76	1.04	1.16	1.24	1.30	1.67	1.91	2.06	1.91	ns
HSTL_II_DCI_18_F	0.70	0.72	0.82	0.76	0.98	1.09	1.16	1.27	1.61	1.85	1.98	1.88	ns
HSTL_II _T_DCI_18_F	0.70	0.72	0.82	0.76	1.04	1.16	1.24	1.30	1.67	1.91	2.06	1.91	ns
DIFF_HSTL_I_F	0.75	0.79	0.92	0.89	1.02	1.14	1.22	1.35	1.66	1.90	2.04	1.96	ns
DIFF_HSTL_II_F	0.75	0.79	0.92	0.89	0.97	1.08	1.15	1.35	1.61	1.84	1.97	1.96	ns
DIFF_HSTL_I_DCI_F	0.75	0.79	0.92	0.76	1.02	1.14	1.22	1.35	1.66	1.90	2.04	1.96	ns

Table 20: **1.8V IOB High Performance (HP) Switching Characteristics *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
LVCMOS12_F8	0.64	0.67	0.78	0.95	1.27	1.42	1.55	1.41	1.91	2.18	2.37	2.02	ns
LVDCI_18	0.47	0.50	0.60	0.86	1.99	2.15	2.35	2.44	2.62	2.91	3.17	3.05	ns
LVDCI_15	0.59	0.62	0.73	0.87	1.98	2.23	2.58	2.40	2.62	2.99	3.40	3.01	ns
LVDCI_DV2_18	0.47	0.50	0.60	0.87	1.99	2.15	2.34	1.86	2.62	2.90	3.17	2.48	ns
LVDCI_DV2_15	0.59	0.62	0.73	0.87	1.98	2.23	2.58	1.83	2.62	2.99	3.40	2.44	ns
HSLVDCI_18	0.68	0.72	0.82	0.86	1.99	2.15	2.35	2.43	2.62	2.91	3.17	3.04	ns
HSLVDCI_15	0.68	0.72	0.82	0.84	1.98	2.23	2.58	2.27	2.62	2.99	3.40	2.88	ns
SSTL18_I_S	0.68	0.72	0.82	0.86	1.02	1.15	1.24	1.41	1.66	1.90	2.07	2.02	ns
SSTL18_II_S	0.68	0.72	0.82	0.87	1.17	1.29	1.37	1.55	1.81	2.05	2.19	2.16	ns
SSTL18_I_DCI_S	0.68	0.72	0.82	0.76	0.92	1.06	1.17	1.32	1.56	1.82	1.99	1.93	ns
SSTL18_II_DCI_S	0.68	0.72	0.82	0.78	0.88	0.98	1.08	1.26	1.51	1.74	1.90	1.87	ns
SSTL18_II_T_DCI_S	0.68	0.72	0.82	0.78	0.92	1.06	1.17	1.32	1.56	1.82	1.99	1.93	ns
SSTL15_S	0.68	0.72	0.82	0.81	0.94	1.06	1.15	1.32	1.58	1.82	1.97	1.93	ns
SSTL15_DCI_S	0.68	0.72	0.82	0.78	0.94	1.06	1.15	1.30	1.57	1.82	1.97	1.91	ns
SSTL15_T_DCI_S	0.68	0.72	0.82	0.80	0.94	1.06	1.15	1.30	1.57	1.82	1.97	1.91	ns
SSTL135_S	0.69	0.72	0.82	0.89	0.97	1.10	1.19	1.35	1.60	1.85	2.01	1.96	ns
SSTL135_DCI_S	0.69	0.72	0.82	0.84	0.97	1.09	1.19	1.33	1.60	1.85	2.01	1.94	ns
SSTL135_T_DCI_S	0.69	0.72	0.82	0.84	0.97	1.09	1.19	1.33	1.60	1.85	2.01	1.94	ns
SSTL12_S	0.69	0.72	0.82	0.95	0.96	1.09	1.18	1.33	1.60	1.84	2.00	1.94	ns
SSTL12_DCI_S	0.69	0.72	0.82	0.91	1.03	1.17	1.27	1.33	1.66	1.92	2.09	1.94	ns
SSTL12_T_DCI_S	0.69	0.72	0.82	0.91	1.03	1.17	1.27	1.33	1.66	1.92	2.09	1.94	ns
DIFF_SSTL18_I_S	0.75	0.79	0.92	0.89	1.02	1.15	1.24	1.43	1.66	1.90	2.07	2.04	ns
DIFF_SSTL18_II_S	0.75	0.79	0.92	0.89	1.17	1.29	1.37	1.55	1.81	2.05	2.19	2.16	ns
DIFF_SSTL18_I_DCI_S	0.75	0.79	0.92	0.76	0.92	1.06	1.17	1.40	1.56	1.82	1.99	2.01	ns
DIFF_SSTL18_II_DCI_S	0.75	0.79	0.92	0.75	0.88	0.98	1.08	1.33	1.51	1.74	1.90	1.94	ns
DIFF_SSTL18_II_T_DCI_S	0.75	0.79	0.92	0.76	0.92	1.06	1.17	1.40	1.56	1.82	1.99	2.01	ns
DIFF_SSTL15_S	0.68	0.72	0.82	0.89	0.94	1.06	1.15	1.32	1.58	1.82	1.97	1.93	ns
DIFF_SSTL15_DCI_S	0.68	0.72	0.82	0.75	0.94	1.06	1.15	1.30	1.57	1.82	1.97	1.91	ns
DIFF_SSTL15_T_DCI_S	0.68	0.72	0.82	0.76	0.94	1.06	1.15	1.38	1.57	1.82	1.97	1.99	ns
DIFF_SSTL135_S	0.69	0.72	0.82	0.91	0.97	1.10	1.19	1.35	1.60	1.85	2.01	1.96	ns
DIFF_SSTL135_DCI_S	0.69	0.72	0.82	0.76	0.97	1.09	1.19	1.33	1.60	1.85	2.01	1.94	ns
DIFF_SSTL135_T_DCI_S	0.69	0.72	0.82	0.76	0.97	1.09	1.19	1.43	1.60	1.85	2.01	2.04	ns
DIFF_SSTL12_S	0.69	0.72	0.82	0.91	0.96	1.09	1.18	1.33	1.60	1.84	2.00	1.94	ns
DIFF_SSTL12_DCI_S	0.69	0.72	0.82	0.78	1.03	1.17	1.27	1.33	1.66	1.92	2.09	1.94	ns
DIFF_SSTL12_T_DCI_S	0.69	0.72	0.82	0.80	1.03	1.17	1.27	1.41	1.66	1.92	2.09	2.02	ns

Table 20: **1.8V IOB High Performance (HP) Switching Characteristics *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
SSTL18_I_F	0.68	0.72	0.82	0.86	0.94	1.06	1.15	1.32	1.58	1.82	1.97	1.93	ns
SSTL18_II_F	0.68	0.72	0.82	0.87	0.97	1.09	1.16	1.36	1.61	1.84	1.99	1.98	ns
SSTL18_I_DCI_F	0.68	0.72	0.82	0.76	0.89	1.02	1.10	1.30	1.53	1.77	1.92	1.91	ns
SSTL18_II_DCI_F	0.68	0.72	0.82	0.78	0.89	1.02	1.10	1.24	1.53	1.77	1.92	1.85	ns
SSTL18_II_T_DCI_F	0.68	0.72	0.82	0.78	0.89	1.02	1.10	1.27	1.53	1.77	1.92	1.88	ns
SSTL15_F	0.68	0.72	0.82	0.81	0.89	1.01	1.09	1.24	1.53	1.77	1.91	1.85	ns
SSTL15_DCI_F	0.68	0.72	0.82	0.78	0.89	1.01	1.09	1.27	1.53	1.77	1.91	1.88	ns
SSTL15_T_DCI_F	0.68	0.72	0.82	0.80	0.89	1.01	1.09	1.27	1.53	1.77	1.91	1.88	ns
SSTL135_F	0.69	0.72	0.82	0.89	0.88	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
SSTL135_DCI_F	0.69	0.72	0.82	0.84	0.89	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
SSTL135_T_DCI_F	0.69	0.72	0.82	0.84	0.89	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
SSTL12_F	0.69	0.72	0.82	0.95	0.88	1.00	1.08	1.26	1.52	1.76	1.90	1.87	ns
SSTL12_DCI_F	0.69	0.72	0.82	0.91	0.91	1.03	1.11	1.24	1.54	1.79	1.93	1.85	ns
SSTL12_T_DCI_F	0.69	0.72	0.82	0.91	0.91	1.03	1.11	1.26	1.54	1.79	1.93	1.87	ns
DIFF_SSTL18_I_F	0.75	0.79	0.92	0.89	0.94	1.06	1.15	1.38	1.58	1.82	1.97	1.99	ns
DIFF_SSTL18_II_F	0.75	0.79	0.92	0.89	0.97	1.09	1.16	1.40	1.61	1.84	1.99	2.01	ns
DIFF_SSTL18_I_DCI_F	0.75	0.79	0.92	0.76	0.89	1.02	1.10	1.36	1.53	1.77	1.92	1.98	ns
DIFF_SSTL18_II_DCI_F	0.75	0.79	0.92	0.75	0.89	1.02	1.10	1.32	1.53	1.77	1.92	1.93	ns
DIFF_SSTL18_II_T_DCI_F	0.75	0.79	0.92	0.76	0.89	1.02	1.10	1.38	1.53	1.77	1.92	1.99	ns
DIFF_SSTL15_F	0.68	0.72	0.82	0.89	0.89	1.01	1.09	1.24	1.53	1.77	1.91	1.85	ns
DIFF_SSTL15_DCI_F	0.68	0.72	0.82	0.75	0.89	1.01	1.09	1.27	1.53	1.77	1.91	1.88	ns
DIFF_SSTL15_T_DCI_F	0.68	0.72	0.82	0.76	0.89	1.01	1.09	1.35	1.53	1.77	1.91	1.96	ns
DIFF_SSTL135_F	0.69	0.72	0.82	0.91	0.88	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
DIFF_SSTL135_DCI_F	0.69	0.72	0.82	0.76	0.89	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
DIFF_SSTL135_T_DCI_F	0.69	0.72	0.82	0.76	0.89	1.00	1.08	1.35	1.52	1.76	1.90	1.96	ns
DIFF_SSTL12_F	0.69	0.72	0.82	0.91	0.88	1.00	1.08	1.26	1.52	1.76	1.90	1.87	ns
DIFF_SSTL12_DCI_F	0.69	0.72	0.82	0.78	0.91	1.03	1.11	1.24	1.54	1.79	1.93	1.85	ns
DIFF_SSTL12_T_DCI_F	0.69	0.72	0.82	0.80	0.91	1.03	1.11	1.33	1.54	1.79	1.93	1.94	ns

Notes:

1. This I/O standard is only available in the 1.8V high-performance (HP) banks.

Table 21 specifies the values of T_{IOTPHZ} and $T_{IOIBUFDISABLE}$. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). $T_{IOIBUFDISABLE}$ is described as the IOB delay from IBUFDISABLE to O output. In HP I/O banks, the internal DCI termination turn-off time is always faster than T_{IOTPHZ} when the DCITERMDISABLE pin is used. In HR I/O banks, the internal IN_TERM termination turn-off time is always faster than T_{IOTPHZ} when the INTERMDISABLE pin is used.

Table 21: **IOB 3-state Output Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{IOTPHZ}	T input to pad high-impedance	0.76	0.86	0.99	0.62	ns
$T_{IOIBUFDISABLE\_HR}$	IBUF turn-on time from IBUFDISABLE to O output for HR I/O banks	1.72	1.89	2.14	2.17	ns
$T_{IOIBUFDISABLE\_HP}$	IBUF turn-on time from IBUFDISABLE to O output for HP I/O banks	1.31	1.46	1.76	1.86	ns

Table 23: **OLOGIC Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T_{ODCK}/T_{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.45/–0.13	0.50/–0.13	0.58/–0.13	0.79/–0.18	ns
T_{OOCECK}/T_{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	0.35/–0.10	ns
T_{OSRCK}/T_{OCKSR}	SR pin Setup/Hold with respect to CLK	0.32/0.18	0.38/0.18	0.70/0.18	0.62/–0.04	ns
T_{OTCK}/T_{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.49/–0.16	0.56/–0.16	0.68/–0.16	0.67/–0.18	ns
T_{OTCECK}/T_{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	0.31/–0.10	ns
Combinatorial						
T_{ODQ}	D1 to OQ out or T1 to TQ out	0.73	0.81	0.97	1.18	ns
Sequential Delays						
T_{OCKQ}	CLK to OQ/TQ out	0.41	0.43	0.49	0.63	ns
$T_{RQ\_OLOGICE2}$	SR pin to OQ/TQ out (HP I/O banks only)	0.63	0.70	0.83	1.12	ns
$T_{GSRQ\_OLOGICE2}$	Global Set/Reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	11.39	ns
$T_{RQ\_OLOGICE3}$	SR pin to OQ/TQ out (HR I/O banks only)	0.63	0.70	0.83	1.12	ns
$T_{GSRQ\_OLOGICE3}$	Global Set/Reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	11.39	ns
Set/Reset						
$T_{RPW\_OLOGICE2}$	Minimum Pulse Width, SR inputs (HP I/O banks only)	0.54	0.54	0.63	0.68	ns, Min
$T_{RPW\_OLOGICE3}$	Minimum Pulse Width, SR inputs (HR I/O banks only)	0.54	0.54	0.63	0.68	ns, Min

Table 31: **Block RAM and FIFO Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$T_{RCCK\_RSTRAM}/T_{RCKC\_RSTRAM}$	Synchronous RSTRAM input	0.27/0.35	0.29/0.37	0.31/0.39	0.34/0.40	ns, Min
$T_{RCCK\_WEA}/T_{RCKC\_WEA}$	Write Enable (WE) input (Block RAM only)	0.38/0.15	0.41/0.16	0.46/0.17	0.54/0.19	ns, Min
$T_{RCCK\_WREN}/T_{RCKC\_WREN}$	WREN FIFO inputs	0.39/0.25	0.39/0.30	0.40/0.37	0.65/0.37	ns, Min
$T_{RCCK\_RDEN}/T_{RCKC\_RDEN}$	RDEN FIFO inputs	0.36/0.26	0.36/0.30	0.37/0.37	0.60/0.38	ns, Min
Reset Delays						
T_{RCO_FLAGS}	Reset RST to FIFO flags/pointers(10)	0.76	0.83	0.93	1.06	ns, Max
$T_{RREC\_RST}/T_{RREM\_RST}$	FIFO reset recovery and removal timing(11)	1.59/–0.68	1.76/–0.68	2.01/–0.68	2.07/–0.60	ns, Max
Maximum Frequency						
$F_{MAX\_BRAM\_WF\_NC}$	Block RAM (Write first and No change modes) When not in SDP RF mode	601.32	543.77	458.09	372.44	MHz
$F_{MAX\_BRAM\_RF\_PERFORMANCE}$	Block RAM (Read first, Performance mode) When in SDP RF mode but no address overlap between port A and port B	601.32	543.77	458.09	372.44	MHz
$F_{MAX\_BRAM\_RF\_DELAYED\_WRITE}$	Block RAM (Read first, Delayed_write mode) When in SDP RF mode and there is possibility of overlap between port A and port B addresses	528.26	477.33	400.80	317.36	MHz
$F_{MAX\_CAS\_WF\_NC}$	Block RAM Cascade (Write first, No change mode) When cascade but not in RF mode	551.27	493.83	408.00	322.48	MHz
$F_{MAX\_CAS\_RF\_PERFORMANCE}$	Block RAM Cascade (Read first, Performance mode) When in cascade with RF mode and no possibility of address overlap/one port is disabled	551.27	493.83	408.00	322.48	MHz
$F_{MAX\_CAS\_RF\_DELAYED\_WRITE}$	When in cascade RF mode and there is a possibility of address overlap between port A and port B	478.27	427.35	350.88	267.38	MHz
F_{MAX_FIFO}	FIFO in all modes without ECC	601.32	543.77	458.09	372.44	MHz
F_{MAX_ECC}	Block RAM and FIFO in ECC configuration	484.26	430.85	351.12	254.13	MHz

Notes:

1. TRACE will report all of these parameters as T_{RCKO_DO}.
2. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO_REG = 0.
4. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO_REG = 1.
6. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
7. $T_{RCKO\_POINTERS}$ includes both $T_{RCKO\_RDCOUNT}$ and $T_{RCKO\_WRCOUNT}$.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. These parameters include both A and B inputs as well as the parity inputs of A and B.
10. T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

DSP48E1 Switching Characteristics

Table 32: **DSP48E1 Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock						
$T_{DSPDCK\_A\_AREG}$/ $T_{DSPCKD\_A\_AREG}$	A input to A register CLK	0.24/ 0.12	0.27/ 0.14	0.31/ 0.16	0.38/ 0.12	ns
$T_{DSPDCK\_B\_BREG}$/$T_{DSPCKD\_B\_BREG}$	B input to B register CLK	0.28/ 0.13	0.32/ 0.14	0.39/ 0.15	0.51/ 0.16	ns
$T_{DSPDCK\_C\_CREG}$/$T_{DSPCKD\_C\_CREG}$	C input to C register CLK	0.15/ 0.15	0.17/ 0.17	0.20/ 0.20	0.31/ 0.21	ns
$T_{DSPDCK\_D\_DREG}$/$T_{DSPCKD\_D\_DREG}$	D input to D register CLK	0.21/ 0.19	0.27/ 0.22	0.35/ 0.26	0.46/ 0.20	ns
$T_{DSPDCK\_ACIN\_AREG}$/$T_{DSPCKD\_ACIN\_AREG}$	ACIN input to A register CLK	0.21/ 0.12	0.24/ 0.14	0.27/ 0.16	0.31/ 0.12	ns
$T_{DSPDCK\_BCIN\_BREG}$/$T_{DSPCKD\_BCIN\_BREG}$	BCIN input to B register CLK	0.22/ 0.13	0.25/ 0.14	0.30/ 0.15	0.34/ 0.16	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock						
$T_{DSPDCK\_\{A, B\}\_MREG\_MULT}$/ $T_{DSPCKD\_B\_MREG\_MULT}$	{A, B,} input to M register CLK using multiplier	2.04/ –0.01	2.34/ –0.01	2.79/ –0.01	3.66/ –0.06	ns
$T_{DSPDCK\_\{A, B\}\_ADREG}$/ $T_{DSPCKD\_ D\_ADREG}$	{A, D} input to AD register CLK	1.09/ –0.02	1.25/ –0.02	1.49/ –0.02	1.94/ –0.23	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock						
$T_{DSPDCK\_\{A, B\}\_PREG\_MULT}$/ $T_{DSPCKD\_\{A, B\}\ \_PREG\_MULT}$	{A, B,} input to P register CLK using multiplier	3.41/ –0.24	3.90/ –0.24	4.64/ –0.24	5.89/ –0.41	ns
$T_{DSPDCK\_D\_PREG\_MULT}$/ $T_{DSPCKD\_D\_PREG\_MULT}$	D input to P register CLK using multiplier	3.33/ –0.62	3.81/ –0.62	4.53/ –0.62	5.70/ –1.42	ns
$T_{DSPDCK\_\{A, B\}\ \_PREG}$/ $T_{DSPCKD\_\{A, B\}\ \_PREG}$	A or B input to P register CLK not using multiplier	1.47/ –0.24	1.68/ –0.24	2.00/ –0.24	2.37/ –0.41	ns
$T_{DSPDCK\_C\_PREG}$/ $T_{DSPCKD\_C\_PREG}$	C input to P register CLK not using multiplier	1.30/ –0.22	1.49/ –0.22	1.78/ –0.22	2.11/ –0.36	ns
$T_{DSPDCK\_PCIN\_PREG}$/ $T_{DSPCKD\_PCIN\_PREG}$	PCIN input to P register CLK	1.12/ –0.13	1.28/ –0.13	1.52/ –0.13	1.81/ –0.21	ns
Setup and Hold Times of the CE Pins						
$T_{DSPDCK\_\{CEA;CEB\}\_\{AREG;BREG\}}$/ $T_{DSPCKD\_\{CEA;CEB\}\_\{AREG;BREG\}}$	{CEA; CEB} input to {A; B} register CLK	0.30/ 0.05	0.36/ 0.06	0.44/ 0.09	0.55/ 0.09	ns
$T_{DSPDCK\_CEC\_CREG}$/ $T_{DSPCKD\_CEC\_CREG}$	CEC input to C register CLK	0.24/ 0.08	0.29/ 0.09	0.36/ 0.11	0.43/ 0.11	ns
$T_{DSPDCK\_CED\_DREG}$/ $T_{DSPCKD\_CED\_DREG}$	CED input to D register CLK	0.31/ –0.02	0.36/ –0.02	0.44/ –0.02	0.58/ 0.12	ns
$T_{DSPDCK\_CEM\_MREG}$/ $T_{DSPCKD\_CEM\_MREG}$	CEM input to M register CLK	0.26/ 0.15	0.29/ 0.17	0.33/ 0.20	0.39/ 0.25	ns
$T_{DSPDCK\_CEP\_PREG}$/ $T_{DSPCKD\_CEP\_PREG}$	CEP input to P register CLK	0.31/ 0.01	0.36/ 0.01	0.45/ 0.01	0.54/ 0.00	ns

Table 32: **DSP48E1 Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Clock to Outs from Pipeline Register Clock to Output Pins						
$T_{DSPCKO\_P\_MREG}$	CLK MREG to P output	1.42	1.64	1.96	2.31	ns
$T_{DSPCKO\_CARRYCASCOUT\_MREG}$	CLK MREG to CARRYCASCOUT output	1.63	1.87	2.24	2.65	ns
$T_{DSPCKO\_P\_ADREG\_MULT}$	CLK ADREG to P output using multiplier	2.30	2.63	3.13	3.90	ns
$T_{DSPCKO\_CARRYCASCOUT\_ADREG\_MULT}$	CLK ADREG to CARRYCASCOUT output using multiplier	2.51	2.87	3.41	4.23	ns
Clock to Outs from Input Register Clock to Output Pins						
$T_{DSPCKO\_P\_AREG\_MULT}$	CLK AREG to P output using multiplier	3.34	3.83	4.55	5.80	ns
$T_{DSPCKO\_P\_BREG}$	CLK BREG to P output not using multiplier	1.39	1.59	1.88	2.24	ns
$T_{DSPCKO\_P\_CREG}$	CLK CREG to P output not using multiplier	1.43	1.64	1.95	2.32	ns
$T_{DSPCKO\_P\_DREG\_MULT}$	CLK DREG to P output using multiplier	3.32	3.80	4.51	5.74	ns
Clock to Outs from Input Register Clock to Cascading Output Pins						
$T_{DSPCKO\_\{ACOUT;\ BCOUT\}\_\{AREG;\ BREG\}}$	CLK (ACOUT, BCOUT) to {A,B} register output	0.55	0.62	0.74	0.87	ns
$T_{DSPCKO\_CARRYCASCOUT\_\{AREG,\ BREG\}\_MULT}$	CLK (AREG, BREG) to CARRYCASCOUT output using multiplier	3.55	4.06	4.84	6.13	ns
$T_{DSPCKO\_CARRYCASCOUT\_\ BREG}$	CLK BREG to CARRYCASCOUT output not using multiplier	1.60	1.82	2.16	2.58	ns
$T_{DSPCKO\_CARRYCASCOUT\_\ DREG\_MULT}$	CLK DREG to CARRYCASCOUT output using multiplier	3.52	4.03	4.79	6.07	ns
$T_{DSPCKO\_CARRYCASCOUT\_\ CREG}$	CLK CREG to CARRYCASCOUT output	1.64	1.88	2.23	2.65	ns
Maximum Frequency						
F_{MAX}	With all registers used	741.84	650.20	547.95	429.37	MHz
F_{MAX_PATDET}	With pattern detector	627.35	549.75	463.61	365.90	MHz
$F_{MAX\_MULT\_NOMREG}$	Two register multiply without MREG	412.20	360.75	303.77	248.32	MHz
$F_{MAX\_MULT\_NOMREG\_PATDET}$	Two register multiply without MREG with pattern detect	374.25	327.65	276.01	225.73	MHz
$F_{MAX\_PREADD\_MULT\_NOADREG}$	Without ADREG	468.82	408.66	342.70	263.44	MHz
$F_{MAX\_PREADD\_MULT\_NOADREG\_PATDET}$	Without ADREG with pattern detect	468.82	408.66	342.70	263.44	MHz
$F_{MAX\_NOPIPELINEREG}$	Without pipeline registers (MREG, ADREG)	306.84	267.81	225.02	177.15	MHz
$F_{MAX\_NOPIPELINEREG\_PATDET}$	Without pipeline registers (MREG, ADREG) with pattern detect	285.23	249.13	209.38	165.32	MHz

MMCM Switching Characteristics

Table 38: **MMCM Specification**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
$MMCM\_F_{INMAX}$	Maximum Input Clock Frequency	1066.00	933.00	800.00	800.00	MHz
$MMCM\_F_{INMIN}$	Minimum Input Clock Frequency	10.00	10.00	10.00	10.00	MHz
$MMCM\_F_{INJITTER}$	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max				
$MMCM\_F_{INDUTY}$	Allowable Input Duty Cycle: 10—49 MHz	25.00	25.00	25.00	25.00	%
	Allowable Input Duty Cycle: 50—199 MHz	30.00	30.00	30.00	30.00	%
	Allowable Input Duty Cycle: 200—399 MHz	35.00	35.00	35.00	35.00	%
	Allowable Input Duty Cycle: 400—499 MHz	40.00	40.00	40.00	40.00	%
	Allowable Input Duty Cycle: >500 MHz	45.00	45.00	45.00	45.00	%
$MMCM\_F_{MIN\_PSCLK}$	Minimum Dynamic Phase Shift Clock Frequency	0.01	0.01	0.01	0.01	MHz
$MMCM\_F_{MAX\_PSCLK}$	Maximum Dynamic Phase Shift Clock Frequency	550.00	500.00	450.00	450.00	MHz
$MMCM\_F_{VCOMIN}$	Minimum MMCM VCO Frequency	600.00	600.00	600.00	600.00	MHz
$MMCM\_F_{VCOMAX}$	Maximum MMCM VCO Frequency	1600.00	1440.00	1200.00	1200.00	MHz
$MMCM\_F_{BANDWIDTH}$	Low MMCM Bandwidth at Typical(1)	1.00	1.00	1.00	1.00	MHz
	High MMCM Bandwidth at Typical(1)	4.00	4.00	4.00	4.00	MHz
$MMCM\_T_{STATPHAOFFSET}$	Static Phase Offset of the MMCM Outputs(2)	0.12	0.12	0.12	0.12	ns
$MMCM\_T_{OUTJITTER}$	MMCM Output Jitter	Note 3				
$MMCM\_T_{OUTDUTY}$	MMCM Output Clock Duty Cycle Precision(4)	0.20	0.20	0.20	0.25	ns
$MMCM\_T_{LOCKMAX}$	MMCM Maximum Lock Time	100.00	100.00	100.00	100.00	µs
$MMCM\_F_{OUTMAX}$	MMCM Maximum Output Frequency	1066.00	933.00	800.00	800.00	MHz
$MMCM\_F_{OUTMIN}$	MMCM Minimum Output Frequency(5)(6)	4.69	4.69	4.69	4.69	MHz
$MMCM\_T_{EXTFDVAR}$	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max				
$MMCM\_RST_{MINPULSE}$	Minimum Reset Pulse Width	5.00	5.00	5.00	5.00	ns
$MMCM\_F_{PFDMAX}$	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	550.00	500.00	450.00	450.00	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300.00	300.00	300.00	300.00	MHz
$MMCM\_F_{PFDMIN}$	Minimum Frequency at the Phase Frequency Detector	10.00	10.00	10.00	10.00	MHz
$MMCM\_T_{FBDELAY}$	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
MMCM Switching Characteristics Setup and Hold						
$T_{MMCMDCK\_PSEN}$/ $T_{MMCMCKD\_PSEN}$	Setup and Hold of Phase Shift Enable	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
$T_{MMCMDCK\_PSINCDEC}$/ $T_{MMCMCKD\_PSINCDEC}$	Setup and Hold of Phase Shift Increment/Decrement	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
$T_{MMCMCKO\_PSDONE}$	Phase Shift Clock-to-Out of PSDONE	0.59	0.68	0.81	0.78	ns
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
$T_{MMCMDCK\_DADDR}$/ $T_{MMCMCKD\_DADDR}$	DADDR Setup/Hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
$T_{MMCMDCK\_DI}$/ $T_{MMCMCKD\_DI}$	DI Setup/Hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min

Table 39: **PLL Specification *(Cont'd)***

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
PLL_F_{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	550.00	500.00	450.00	450.00	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300.00	300.00	300.00	300.00	MHz
PLL_F_{PFDMIN}	Minimum Frequency at the Phase Frequency Detector	19.00	19.00	19.00	19.00	MHz
PLL_$T_{FBDELAY}$	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
Dynamic Reconfiguration Port (DRP) for PLL Before and After DCLK						
T_{PLLCCK_DADDR}/ T_{PLLCKC_DADDR}	Setup and hold of D address	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_{PLLCCK_DI}/ T_{PLLCKC_DI}	Setup and hold of D input	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_{PLLCCK_DEN}/ T_{PLLCKC_DEN}	Setup and hold of D enable	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T_{PLLCCK_DWE}/ T_{PLLCKC_DWE}	Setup and hold of D write enable	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T_{PLLCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	0.70	ns, Max
F_{DCK}	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The PLL does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any PLL outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard. See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.

Table 47: **Clock-Capable Clock Input Setup and Hold With PLL**

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard.(1)							
$T_{PSPLLCC}$/ $T_{PHPLLCC}$	No Delay clock-capable clock input and IFF(2) with PLL	XC7K70T	2.75/–0.32	3.04/–0.32	3.33/–0.32	2.42/–0.54	ns
		XC7K160T	2.85/–0.31	3.16/–0.31	3.46/–0.31	2.59/–0.56	ns
		XC7K325T	2.91/–0.27	3.24/–0.27	3.54/–0.27	2.80/–0.56	ns
		XC7K355T	2.79/–0.27	3.12/–0.27	3.40/–0.27	2.67/–0.52	ns
		XC7K410T	2.91/–0.27	3.24/–0.27	3.53/–0.27	2.78/–0.56	ns
		XC7K420T	2.83/–0.20	3.12/–0.20	3.41/–0.20	2.61/–0.50	ns
		XC7K480T	2.83/–0.20	3.12/–0.20	3.41/–0.20	2.61/–0.50	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 48: **Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIO for SSTL15 Standard.						
T_{PSCS}/T_{PHCS}	Setup/Hold of I/O clock for HR I/O banks	–0.36/1.36	–0.36/1.50	–0.36/1.70	–0.44/1.87	ns
	Setup/Hold of I/O clock for HP I/O banks	–0.34/1.39	–0.34/1.53	–0.34/1.73	–0.44/1.87	ns

Table 49: **Sample Window**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{SAMP}	Sampling Error at Receiver Pins(1)	0.51	0.56	0.61	0.56	ns
T_{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO(2)	0.30	0.35	0.40	0.35	ns

Notes:

1. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
   - CLK0 MMCM jitter
   - MMCM accuracy (phase offset)
   - MMCM phase shift resolution

   These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 56: **GTX Transceiver PLL /Lock Time Adaptation**

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T_{LOCK}	Initial PLL lock		–	–	1	ms
T_{DLOCK}	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	–	50,000	37 x10^6	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		–	50,000	2.3 x10^6	UI

Table 57: **GTX Transceiver User Clock Switching Characteristics(1)(2)**

Symbol	Description	Conditions	Speed Grade				Units
			1.0V			0.9V	
			-3(3)	-2/-2L(3)	-1(4)	-2L(5)	
F_{TXOUT}	TXOUTCLK maximum frequency		412.54	412.54	312.50	237.53	MHz
F_{RXOUT}	RXOUTCLK maximum frequency		412.54	412.54	312.50	237.53	MHz
F_{TXIN}	TXUSRCLK maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz
		32-bit data path	391.08	322.37	250.00	206.27	MHz
F_{RXIN}	RXUSRCLK maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz
		32-bit data path	391.08	322.37	250.00	206.27	MHz
F_{TXIN2}	TXUSRCLK2 maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz
		32-bit data path	391.08	322.37	250.00	206.27	MHz
		64-bit data path	195.54	161.19	125.00	103.14	MHz
F_{RXIN2}	RXUSRCLK2 maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz
		32-bit data path	391.08	322.37	250.00	206.27	MHz
		64-bit data path	195.54	161.19	125.00	103.14	MHz

Notes:

1. Clocking must be implemented as described in UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide*.
2. These frequencies are not supported for all possible transceiver configurations.
3. For speed grades -3, -2, -2L (1.0V), a 16-bit data path can only be used for speeds less than 6.6 Gb/s.
4. For speed grade -1, a 16-bit data path can only be used for speeds less than 5.0 Gb/s.
5. For speed grade -2L (0.9V), a 16-bit data path can only be used for speeds less than 3.8 Gb/s.

Table 58: **GTX Transceiver Transmitter Switching Characteristics**

Symbol	Description	Condition	Min	Typ	Max	Units
F_{GTXTX}	Serial data rate range		0.500	–	F_{GTXMAX}	Gb/s
T_{RTX}	TX Rise time	20%–80%	–	40	–	ps
T_{FTX}	TX Fall time	80%–20%	–	40	–	ps
T_{LLSKEW}	TX lane-to-lane skew(1)		–	–	500	ps
$V_{TXOOBVDPP}$	Electrical idle amplitude		–	–	15	mV
$T_{TXOOBTRANSITION}$	Electrical idle transition time		–	–	140	ns
$TJ_{12.5}$	Total Jitter(2)(4)	12.5 Gb/s	–	–	0.28	UI
$DJ_{12.5}$	Deterministic Jitter(2)(4)		–	–	0.17	UI
$TJ_{11.18}$	Total Jitter(2)(4)	11.18 Gb/s	–	–	0.28	UI
$DJ_{11.18}$	Deterministic Jitter(2)(4)		–	–	0.17	UI

Table 59: **GTX Transceiver Receiver Switching Characteristics**

Symbol	Description		Min	Typ	Max	Units
F_{GTXRX}	Serial data rate	RX oversampler not enabled	0.500	–	F_{GTXMAX}	Gb/s
$T_{RXELECIDLE}$	Time for RXELECIDLE to respond to loss or restoration of data		–	10	–	ns
$RX_{OOBVDPP}$	OOB detect threshold peak-to-peak		60	–	150	mV
RX_{SST}	Receiver spread-spectrum tracking(1)	Modulated @ 33 KHz	–5000	–	0	ppm
RX_{RL}	Run length (CID)		–	–	512	UI
RX_{PPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	–1250	–	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	–700	–	700	ppm
		Bit rates > 8.0 Gb/s	–200	–	200	ppm
SJ Jitter Tolerance(2)						
$JT\_SJ_{12.5}$	Sinusoidal Jitter (QPLL)(3)	12.5 Gb/s	0.3	–	–	UI
$JT\_SJ_{11.18}$	Sinusoidal Jitter (QPLL)(3)	11.18 Gb/s	0.3	–	–	UI
$JT\_SJ_{10.32}$	Sinusoidal Jitter (QPLL)(3)	10.32 Gb/s	0.3	–	–	UI
$JT\_SJ_{9.95}$	Sinusoidal Jitter (QPLL)(3)	9.95 Gb/s	0.3	–	–	UI
$JT\_SJ_{9.8}$	Sinusoidal Jitter (QPLL)(3)	9.8 Gb/s	0.3	–	–	UI
$JT\_SJ_{8.0}$	Sinusoidal Jitter (QPLL)(3)	8.0 Gb/s	0.44	–	–	UI
$JT\_SJ_{6.6\_QPLL}$	Sinusoidal Jitter (QPLL)(3)	6.6 Gb/s	0.48	–	–	UI
$JT\_SJ_{6.6\_CPLL}$	Sinusoidal Jitter (CPLL)(3)	6.6 Gb/s	0.44	–	–	UI
$JT\_SJ_{5.0}$	Sinusoidal Jitter (CPLL)(3)	5.0 Gb/s	0.44	–	–	UI
$JT\_SJ_{4.25}$	Sinusoidal Jitter (CPLL)(3)	4.25 Gb/s	0.44	–	–	UI
$JT\_SJ_{3.75}$	Sinusoidal Jitter (CPLL)(3)	3.75 Gb/s	0.44	–	–	UI
$JT\_SJ_{3.2}$	Sinusoidal Jitter (CPLL)(3)	3.2 Gb/s(4)	0.45	–	–	UI
$JT\_SJ_{3.2L}$	Sinusoidal Jitter (CPLL)(3)	3.2 Gb/s(5)	0.45	–	–	UI
$JT\_SJ_{2.5}$	Sinusoidal Jitter (CPLL)(3)	2.5 Gb/s(6)	0.5	–	–	UI
$JT\_SJ_{1.25}$	Sinusoidal Jitter (CPLL)(3)	1.25 Gb/s(7)	0.5	–	–	UI
JT_SJ_{500}	Sinusoidal Jitter (CPLL)(3)	500 Mb/s	0.4	–	–	UI
SJ Jitter Tolerance with Stressed Eye(2)						
$JT\_TJSE_{3.2}$	Total Jitter with Stressed Eye(8)	3.2 Gb/s	0.70	–	–	UI
$JT\_TJSE_{6.6}$		6.6 Gb/s	0.70	–	–	UI
$JT\_SJSE_{3.2}$	Sinusoidal Jitter with Stressed Eye(8)	3.2 Gb/s	0.1	–	–	UI
$JT\_SJSE_{6.6}$		6.6 Gb/s	0.1	–	–	UI

Notes:

1. Using RXOUT_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 10 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
5. CPLL frequency at 1.6 GHz and RXOUT_DIV = 1.
6. CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
7. CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
8. Composite jitter with RX and LPM or DFE mode.

Table 63: **CEI-6G and CEI-11G Protocol Characteristics**

Description	Line Rate (Mb/s)	Interface	Min	Max	Units
CEI-6G Transmitter Jitter Generation					
Total transmitter jitter(1)	4976–6375	CEI-6G-SR	–	0.3	UI
		CEI-6G-LR	–	0.3	UI
CEI-6G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance(1)	4976–6375	CEI-6G-SR	0.6	–	UI
		CEI-6G-LR	0.95	–	UI
CEI-11G Transmitter Jitter Generation					
Total transmitter jitter(2)	9950–11100	CEI-11G-SR	–	0.3	UI
		CEI-11G-LR/MR	–	0.3	UI
CEI-11G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance(2)	9950–11100	CEI-11G-SR	0.65	–	UI
		CEI-11G-MR	0.65	–	UI
		CEI-11G-LR	0.825	–	UI

Notes:

1. Tested at most commonly used line rate of 6250 Mb/s using 390.625 MHz reference clock.
2. Tested at line rate of 9950 Mb/s using 155.46875 MHz reference clock and 11100 Mb/s using 173.4375 MHz reference clock.

Table 64: **SFP+ Protocol Characteristics**

Description	Line Rate (Mb/s)	Min	Max	Units
SFP+ Transmitter Jitter Generation				
Total transmitter jitter	9830.40(1)	–	0.28	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			
SFP+ Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	9830.40(1)	0.7	–	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			

Notes:

1. Line rated used for CPRI over SFP+ applications.

XADC Specifications

Table 67: **XADC Specifications**

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
V_{CCADC} = 1.8V ± 5%, V_{REFP} = 1.25V, V_{REFN} = 0V, ADCCLK = 26 MHz, T_j = –40°C to 100°C, Typical values at T_j=+40°C						
ADC Accuracy(1)						
Resolution			12	–	–	Bits
Integral Nonlinearity(2)	INL		–	–	±3	LSBs
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	LSBs
Offset Error		Offset calibration enabled	–	–	±6	LSBs
Gain Error		Gain calibration disabled	–	–	±0.5	%
Offset Matching		Offset calibration enabled	–	–	4	LSBs
Gain Matching		Gain calibration disabled	–	–	0.3	%
Sample Rate			0.1	–	1	MS/s
Signal to Noise Ratio(2)	SNR	F_{SAMPLE} = 500KS/s, F_{IN} = 20KHz	60	–	–	dB
RMS Code Noise		External 1.25V reference	–	–	2	LSBs
		On-chip reference	–	3	–	LSBs
Total Harmonic Distortion(2)	THD	F_{SAMPLE} = 500KS/s, F_{IN} = 20KHz	–	70	–	dB
ADC Accuracy at Extended Temperatures (-55°C to 125°C)						
Resolution			10	–	–	Bits
Integral Nonlinearity(2)	INL		–	–	±1	LSB (at 10 bits)
Differential Nonlinearity	DNL	No missing codes, guaranteed monotonic	–	–	±1	
Analog Inputs(3)						
ADC Input Ranges		Unipolar operation	0	–	1	V
		Bipolar operation	–0.5	–	+0.5	V
		Unipolar common mode range (FS input)	0	–	+0.5	V
		Bipolar common mode range (FS input)	+0.5	–	+0.6	V
Maximum External Channel Input Ranges		Adjacent channels set within these ranges should not corrupt measurements on adjacent channels	–0.1	–	V_{CCADC}	V
Auxiliary Channel Full Resolution Bandwidth	FRBW		250	–	–	KHz
On-Chip Sensors						
Temperature Sensor Error		T_j = –40°C to 100°C.	–	–	±4	°C
		T_j = –55°C to +125°C	–	–	±6	°C
Supply Sensor Error		Measurement range of V_{CCAUX} 1.8V ±5% T_j = –40°C to +100°C	–	–	±1	%
		Measurement range of V_{CCAUX} 1.8V ±5% T_j = –55°C to +125°C	–	–	±2	%
Conversion Rate(4)						
Conversion Time - Continuous	t_{CONV}	Number of ADCCLK cycles	26	–	32	Cycles
Conversion Time - Event	t_{CONV}	Number of CLK cycles	–	–	21	Cycles
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	250	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	26	MHz
DCLK Duty Cycle			40	–	60	%

Table 67: **XADC Specifications *(Cont'd)***

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
XADC Reference[5]						
External Reference	V_{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
On-Chip Reference		Ground V_{REFP} pin to AGND, T_j = –40°C to 100°C	1.2375	1.25	1.2625	V

Notes:

1. Offset and gain errors are removed by enabling the XADC automatic gain calibration feature. The values are specified for when this feature is enabled.
2. Only specified for new BitGen option XADCEnhancedLinearity = ON.
3. See the ADC chapter in UG480: *7 Series FPGAs XADC User Guide* for a detailed description.
4. See the Timing chapter in UG480: *7 Series FPGAs XADC User Guide* for a detailed description.
5. Any variation in the reference voltage from the nominal V_{REFP} = 1.25V and V_{REFN} = 0V will result in a deviation from the ideal transfer function. This also impacts the accuracy of the internal sensor measurements (i.e., temperature and power supply). However, for external ratiometric type applications allowing reference to vary by ±4% is permitted. On-chip reference variation is ±1%.

Configuration Switching Characteristics

Table 68: **Configuration Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Power-up Timing Characteristics						
T_{PL}[1]	Program latency	5	5	5	5	ms, Max
T_{POR}[1]	Power-on reset (50 ms ramp rate time)	10/50	10/50	10/50	10/50	ms, Min/Max
	Power-on reset (1 ms ramp rate time)	10/35	10/35	10/35	10/35	ms, Min/Max
$T_{PROGRAM}$	Program pulse width	250	250	250	250	ns, Min
CCLK Output (Master Mode)						
T_{ICCK}	Master CCLK output delay	150	150	150	150	ns, Min
T_{MCCKL}	Master CCLK clock Low time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
T_{MCCKH}	Master CCLK clock High time duty cycle	40/60	40/60	40/60	40/60	%, Min/Max
F_{MCCK}	Master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
	Master CCLK frequency for AES encrypted x16	50.00	50.00	50.00	35.00	MHz, Max
F_{MCCK_START}	Master CCLK frequency at start of configuration	3.00	3.00	3.00	3.00	MHz, Typ
$F_{MCCKTOL}$	Frequency tolerance, master mode with respect to nominal CCLK	±50	±50	±50	±50	%, Max
CCLK Input (Slave Modes)						
T_{SCCKL}	Slave CCLK clock minimum Low time	2.50	2.50	2.50	2.50	ns, Min
T_{SCCKH}	Slave CCLK clock minimum High time	2.50	2.50	2.50	2.50	ns, Min
F_{SCCK}	Slave CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
EMCCLK Input (Master Mode)						
T_{EMCCKL}	External master CCLK Low time	2.50	2.50	2.50	2.50	ns, Min
T_{EMCCKH}	External master CCLK High time	2.50	2.50	2.50	2.50	ns, Min
F_{EMCCK}	External master CCLK frequency	100.00	100.00	100.00	70.00	MHz, Max
Internal Configuration Access Port						
F_{ICAPCK}	Internal configuration access port (ICAPE2)	100.00	100.00	100.00	70.00	MHz, Max

Table 68: **Configuration Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Master/Slave Serial Mode Programming Switching						
T_{DCCK}/T_{CCKD}	DIN Setup/Hold	4.00/0.00	4.00/0.00	4.00/0.00	5.00/0.00	ns, Min
T_{CCO}	DOUT clock to out	8.00	8.00	8.00	9.00	ns, Max
SelectMAP Mode Programming Switching						
T_{SMDCCK}/T_{SMCCKD}	D[31:00] Setup/Hold	4.00/0.00	4.00/0.00	4.00/0.00	4.50/0.00	ns, Min
$T_{SMCSCCK}/T_{SMCCKCS}$	CSI_B Setup/Hold	4.00/0.00	4.00/0.00	4.00/0.00	5.00/0.00	ns, Min
T_{SMWCCK}/T_{SMCCKW}	RDWR_B Setup/Hold	10.00/0.00	10.00/0.00	10.00/0.00	12.00/0.00	ns, Min
$T_{SMCKCSO}$	CSO_B clock to out (330 Ω pull-up resistor required)	7.00	7.00	7.00	8.00	ns, Max
T_{SMCO}	D[31:00] clock to out in readback	8.00	8.00	8.00	10.00	ns, Max
F_{RBCCK}	Readback frequency	100.00	100.00	100.00	70.00	MHz, Max
Boundary-Scan Port Timing Specifications						
T_{TAPTCK}/T_{TCKTAP}	TMS and TDI Setup/Hold	3.00/2.00	3.00/2.00	3.00/2.00	3.00/2.00	ns, Min
T_{TCKTDO}	TCK falling edge to TDO output	7.00	7.00	7.00	8.50	ns, Max
F_{TCK}	TCK frequency	66.00	66.00	66.00	50.00	MHz, Max
BPI Master Flash Mode Programming Switching						
T_{BPICCO}(2)	A[28:00], RS[1:0], FCS_B, FOE_B, FWE_B, ADV_B clock to out	8.50	8.50	8.50	10.00	ns, Max
T_{BPIDCC}/T_{BPICCD}	D[15:00] Setup/Hold	4.00/0.00	4.00/0.00	4.00/0.00	4.50/0.00	ns, Min
SPI Master Flash Mode Programming Switching						
T_{SPIDCC}/T_{SPICCD}	D[03:00] Setup/Hold	3.00/0.00	3.00/0.00	3.00/0.00	3.00/0.00	ns, Min
T_{SPICCM}	MOSI clock to out	8.00	8.00	8.00	9.00	ns, Max
$T_{SPICCFC}$	FCS_B clock to out	8.00	8.00	8.00	9.00	ns, Max

Notes:

1. To support longer delays in configuration, use the design solutions described in UG470: *7 Series FPGA Configuration User Guide*.
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.

eFUSE Programming Conditions

Table 69 lists the programming conditions specifically for eFUSE. For more information, see UG470: *7 Series FPGA Configuration User Guide*.

Table 69: **eFUSE Programming Conditions(1)**

Symbol	Description	Min	Typ	Max	Units
I_{FS}	V_{CCAUX} supply current	–	–	115	mA
t_j	Temperature range	15	–	125	°C

Notes:

1. The FPGA must not be configured during eFUSE programming.